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PATENT ²⁸⁸²
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Inventors: Jeffrey T. Fanton, et al.

Application No.: 10/053,373

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For: X-RAY REFLECTANCE
MEASUREMENT SYSTEM WITH
ADJUSTABLE RESOLUTION

Confirmation No.: 2873

Group Art Unit: 2882

Examiner: Irakli Kiknadze

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